Search Notes					

Application/Control No.	Applicant(s)/Patent	under
10/644,996	CHUN, CHANG-HY	'EN
Examiner	Art Unit	
Pierre-Louis Desir	2617	

SEARCHED			
Class	Subclass	Date	Examiner
455	. 442	2/21/2007	PD
455	436	2/21/2007	PD
455	522	2/21/2007	PD
455	434	2/21/2007	PD
370	352	2/21/2007	PD

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH I (INCLUDING SEAR			)
		DATE	EXMR
EAST		2/21/2007	PD
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